

JFET/MOSFET Tests (LIST)

The following is a list of available tests shown in John Lenk's book "McGraw-Hill Electronic Testing Handbook"...

NOTE: most of these tests can be used for either JFETs or MOSFETs.

FET control-voltage tests

- $V_{gs(off)}$ test p237
- $V_{ds(th)}$ or $V_{gs(on)}$ test p238

FET operating-voltage tests

- $V_{ds(off)}$ and $V_{ds(on)}$ saturation tests p239

FET operating-current tests

- I_{dss} test p239
- $I_{d(on)}$ test p240
- $I_{d(off)}$ test p240

JFET and MOSFET voltage-breakdown tests

- $V_{(br)gss}$ and $V_{(br)dgo}$ testing p240

FET gate-leakage tests

- I_{gss} test p241

Dual-gate FET tests

- $V_{g1s(off)}$ and $V_{g2s(off)}$ tests p241

Dual-gate voltage-breakdown tests

- $V_{(br)g1ssf}$ p242

Dual-gate current tests

- I_{ds} test p242

FET dynamic characteristics

- y parameter testing/measurements p242

FET amplification factor

p248

cont.

FET capacitance tests	
• Ciss - input capacitance tests	p249
• Coss - output capacitance tests	p250
• Crss - reverse transfer capacitance tests	p251
• Cd(sub) - FET element capacitance tests	p251
FET channel-resistance tests	
• Rds(on) and Rds(off) tests	p252
FET switching tests	p253
FET gain tests	
• FET Gps-gain test	p254
• FET conversion-gain tests	p254
FET noise figure tests	
• Nf test	p257
FET cross modulation tests	
• FET intermodulation tests	p257
FET tests using a curve tracer	p257
FET transconductance (gain) measure	p259

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